CLAIMS

1. An inspection system for inspection of a plurality of chips, the inspection system comprising:

a first storage location configured to store a first set of chips of the plurality of chips, the first set of chips collected by a dealer from a player, each chip of the plurality of chips including an radio-frequency identification (RFID) tag embedded in the chip;

a first reading device configured to read, for each chip of the first set of chips, the RFID tag of the chip stored at the first storage location; and

a control device configured to, based on the number of the RFID tags read by the first reading device being less than the number of the chips stored in the first storage location, determine that there is at least one abnormal chip of the first set of chips, the at least one abnormal chip associated with an abnormal RFID tag.

2. The inspection system according to claim 1, further comprising:

an acquiring device configured detect the first set of chips stored at the first storage location by means other than RFID to acquire the number of the first set of chips stored at the first storage location,

wherein the control device is further configured to determine that there is at least one abnormal chip based

on the number of the RFID tags read by the first reading device is less than the number of first set of chips acquired by the acquiring device.

3. An inspection system according to claim 2, wherein the acquiring device comprises:

an image sensor configured to capture an image of the first set of chips stored at the first storage location; and

an analyzing device configured to acquire the number of first set of chips stored at the first storage location based on the image.

4. The inspection system according to claim 1, wherein the number of the first set of chips stored at the first storage location is a predetermined number.

5. The inspection system according to claim 4, further comprising:

a storage device configured to store the predetermined number of the plurality of chips,

wherein the control device is further configured to determine that there is an abnormal chip when the number of the RFID tags read by the first reading device is less than the predetermined number.

6. The inspection system according to claim 1, further comprising:

a second storage location configured to store a second set of chips of the plurality of chips, the second set of chips include one or more chips of the first set of chips stored at the first storage location and transferred to the second storage location; and

a second reading device configured to read, for each chip of the second set of chip, the RFID tag of the chip stored at the second storage location;

wherein the control device is configured to, based on the number of the RFID tags read by the second reading device being less than the number of the chips stored in the second storage location, determine that there is an abnormal chip of the second set of chips, the abnormal chip associated with an RFID tag that is abnormal.

7. The inspection system according to claim 6, wherein the second storage location is provided in a vicinity of the first storage location.

8. The inspection system according to claim 6, wherein the first storage location and the second storage location are provided in the same chip tray.

9. The inspection system according to claim 1, further comprising:

a management device configured to store identification information of the plurality of chips,

wherein, for each chip of the plurality of chips:

the RFID tag of the chip is configured to store chip identification information of the chip, and

the control device is further configured to determine an authenticity of the at least one abnormal chip based on whether or not the chip identification information read from the RFID tag by the first reading device is stored in the management device.

10. The inspection system according to claim 1, further comprising a display device configured to display an output associated with the number of the RFID tags read by the first reading device to enable a comparison based on the number of the chips stored at the first storage location and the number of the RFID tags read by the first reading device.

11. The inspection system according to claim 10, wherein the display device is further configured to display the number of the first set of chips stored in the first storage location.

12. The inspection system according to claim 10, further comprising:

an image capturing device configured to capture an image of side faces of the first set of chips at the first storage location,

wherein the display device is further configured to display an output that indicates that there is a discrepancy based on a difference between the number of the chips captured in the image does and the number of the RFID tags read by the first reading device.

13. An inspection system for inspection of plurality of chips, the inspection system comprising:

a first storage location configured to store a first set of chips of a plurality of chips, each chip of the plurality of chips including a radio-frequency identification (RFID) tag embedded in the chip;

a first reading device configured to read, for each chip of the first set of chips, the RFID tag of the chip stored at the first storage location; and

a display device configured to display an output associated with the number of the RFID tags read by the first reading device to enable a comparison based on the number of the chips stored at the first storage location and the number of the RFID tags read by the first reading device.

14. The inspection system according to claim 13, further comprising:

a second storage location different from the first storage location and configured to store a second set of chips of the plurality of the chips; and

a second reading device configured to read, for each chip of the second set of chips, the RFID tag of the chip stored at the second storage location.

15. The inspection system according to claim 13, wherein the display device is further configured to display the number of chips stored in the first storage location.

16. The inspection system according to claim 13, further comprising:

an image capturing device configured to capture an image of side faces of the first set of chips at the first storage location,

wherein the display device is further configured to display an output that indicates that there is a discrepancy based on a difference between the number of the chips captured in the image does and the number of the RFID tags read by the first reading device.

17. A method comprising:

at a control device of an inspection system for a plurality of chips, each chip of the plurality of chips

including a radio-frequency identification (RFID) tag is embedded in the chip, performing operations comprising:

receiving a first indicator of a number of a first set of chips of a plurality of chips, the first set of chips stored at a storage location configured to store one or more chips collected by a dealer from a player;

receiving, from a first reading device, a first indication of a number of RFID tags read by the first reading device of the first set of chips stored at the storage location; and

generating an output based on a determination that the number of the RFID tags read by the first reading device being different than the number of the first set of chips stored at the storage location.

18. The method according to claim 17, wherein generating the output includes generating the output based on the number of the RFID tags read by the first reading device being less than the number of the chips stored at the storage location.

19. The method according to claim 17, wherein the output is associated with an indication that at least one chip of the first set of chips includes an RFID tag that is abnormal.

20. The method according to claim 17, further comprising:

performing a comparison based on the number of RFID tags read by the first reading device and the number of the first set of chips stored at the storage location;

determining that the number of the RFID tags read by the first reading device is different than the number of the first set of chips stored at the storage location; and

providing the output to a device configured to generate an alarm based on the output.